PCN N	lumber:	20140319001	LB				PCN Date:	09/01/2015	
Title:	Add Cu as Alternative Wire Base Metal for Selected Device(s) on QFN, QFP and SOT-23 packages								
Custo	mer Contact:	PCN Manager		Dept:	Quality S	ervi	ces		
Chang	Change Type:								
	Assembly Site			esign			Wafer Bump S	ite	
	Assembly Proce	ess		ata Sheet			Wafer Bump M	aterial	
$\boxtimes$	Assembly Mate	rials	P	art number c	hange		Wafer Bump Process		
	Mechanical Spe	cification		est Site			Wafer Fab Site		
	Packing/Shippi	ng/Labeling	T	est Process			Wafer Fab Mat		
							Wafer Fab Prod	cess	
				PCN Detail	S				
Descr	iption of Chan	ge:							
Texas device piece	Revision B is to remove select devices in the Product Affected Section (with strikethrough) and highlighted in yellow. These devices were inadvertently added and not affected by this change. The other devices listed below with a strikethrough were retracted under revision A of PCN20140319001.  Texas Instruments is pleased to announce the qualification of Cu as an additional bond wire option for devices listed in "Product affected" section below. Devices will remain in current assembly facility and piece part changes as follows.  Group 1 Device: No other piece part change, Only Au to Cu wire  Group 2 Device: Changes Wire Composition and Wire Diameter  From To								
	Wire	0.96	mil Au		0.80 mil Cu				
Grour	3 Device: Cha	nges Mold Co	mpour	nd. Wire Con	nnosition a	nd \	Wire Diameter		
O. our	Devicer ena		rom		To				
	Mold Compound			28	450413				
	Wire	0.60, 0.80	•		30, 1.0 mil C	2u			
Reaso	on for Change:				,				
1) To ele 2) Ma 3) Cu Antici None.	align with world align with world ectrical propertie eximize flexibility is easier to obtain the compact of the	s within our Ass ain and stock on Fit, Form, F	embly/	Test production, Quality o	on sites. r Reliability			tive):	
None.									

Product Affected: Group 1 devices - No other piece part change, Only Au to Cu wire							
TPS65633ARTER							
Product Affected: Group 2 devices - Changes Wire Composition and Wire Diameter							
DRV91670PHP DRV91670PHP-MC DRV91670PHPR							
Product Affected: Group	Product Affected: Group 3 devices - Changes Mold Compound, Wire Composition and Wire Diameter						
74AHC1G125DBVRE4	SN74AHC1G08DBVR	SN74LVC1G32DBVRG4	TS5A4594DBVRE4				
74AHC1G125DBVRG4	SN74AHC1G08DBVRE4	SN74LVC1G34DBVR	TS5A4594DBVRG4				
74AHC1G126DBVRE4	SN74AHC1G08DBVRG4	SN74LVC1G34DBVRE4	SN74AHC1G02DBVT				
74AHC1G126DBVRG4	SN74AHC1G125DBVR	SN74LVC1G34DBVRG4	SN74AHC1G86DBV6				
74AHC1GU04DBVRE4	SN74AHC1G126DBVR	SN74LVC1G66DBVR	SN74AHC1G86DBVT				
74AHC1GU04DBVRG4	SN74AHC1G86DBVR	SN74LVC1G66DBVRE4	SN74AHC1GU04DBVT				
74AHCT1G00DBVRE4	SN74AHC1G86DBVRE4	SN74LVC1G66DBVRG4	SN74AHCT1G00DBVT				
74AHCT1G00DBVRG4	SN74AHC1G86DBVRG4	SN74LVC1G79DBVR	SN74AHCT1G04DBVT				
74AHCT1G04DBVRE4	SN74AHC1GU04DBVR	SN74LVC1G79DBVRE4	SN74AHCT1G125DBVT				
74AHCT1G04DBVRG4	SN74AHCT1G00DBVR	SN74LVC1G79DBVRG4	SN74AHCT1G86DBV6				
74AHCT1G08DBVRE4	SN74AHCT1G04DBVR	SN74LVC1G80DBVR	SN74AHCT1G86DBVT				
74AHCT1G08DBVRG4	SN74AHCT1G08DBVR	SN74LVC1G80DBVRE4	SN74AUC1G04DBVR				
74AHCT1G125DBVRE4	SN74AHCT1G125DBVR	SN74LVC1G80DBVRG4	SN74AUC1G08DBVR				
74AHCT1G125DBVRG4	SN74AHCT1G126DBVR	SN74LVC1G86DBVR	SN74AUC1G125DBVR				
74AHCT1G126DBVRE4	SN74AHCT1G32DBVR	SN74LVC1G86DBVRE4	SN74AUC1G240DBVR				
74AHCT1G126DBVRG4	SN74AHCT1G86DBVR	SN74LVC1G86DBVRG4	SN74AUP1G04DBVT				
74AHCT1G32DBVRE4	SN74AUP1G04DBVR	SN74LVC1GU04DBVR	SN74AUP1G14DBVR				
74AHCT1G32DBVRG4	SN74AUP1G04DBVRE4	TL343IDBVR	SN74AUP1G32DBVR				
74AHCT1G86DBVRE4	SN74AUP1G04DBVRG4	TL343IDBVRE4	SN74AUP1G34DBVR				
74AHCT1G86DBVRG4	SN74AUP1G07DBVR	TL343IDBVRG4	SN74CBT1G384DBVR				
74AUP1G125DBVRE4	SN74AUP1G07DBVRE4	TL431ACDBVR	SN74CBT1G384DBVT				
74AUP1G125DBVRG4	SN74AUP1G07DBVRG4	TL431ACDBVRE4	SN74CBTD1G125DBVR				
74CBT1G125DBVRE4	SN74AUP1G125DBVR	TL431ACDBVRG4	SN74CBTD1G125DBVT				
74CBT1G125DBVRG4	SN74CBT1G125DBVR	TL431CDBVR	SN74CBTD1G384DBVR				
74CBTLV1G125DBVRE4	SN74CBTLV1G125DBVR	TL431CDBVRE4	SN74LVC1G02DBVT				
74CBTLV1G125DBVRG4	SN74LVC1G02DBVR	TL431CDBVRG4	SN74LVC1G06DBVT				
74LVC1G126DBVRE4	SN74LVC1G02DBVRE4	TL431IDBVR	SN74LVC1G07DBVT				
74LVC1G126DBVRG4	SN74LVC1G02DBVRG4	TL431IDBVRE4	SN74LVC1G132DBVT				
74LVC1G132DBVRE4	SN74LVC1G06DBVR	TL431IDBVRG4	SN74LVC1G14DBVT				
74LVC1G132DBVRG4	SN74LVC1G06DBVRE4	TLV431AIDBVR	SN74LVC1G240DBVT				
74LVC1G240DBVRE4	SN74LVC1G06DBVRG4	TLV431AIDBVRE4	SN74LVC1G32DBVT				
74LVC1G240DBVRG4	SN74LVC1G07DBVR	TLV431AIDBVRG4	SN74LVC1G34DBVT				
74LVC1GU04DBVRE4	SN74LVC1G07DBVRE4	TLV431CDBVR	SN74LVC1G66DBVT				
74LVC1GU04DBVRG4	SN74LVC1G07DBVRG4	TLV431CDBVRE4	SN74LVC1G79DBVT				
SN003166DBVR	SN74LVC1G126DBVR	TLV431CDBVRG4	SN74LVC1G80DBVT				
SN1003028DBVR	SN74LVC1G132DBVR	TLV431IDBVR	SN74LVC1G86DBVT				
SN74AHC1G02DBVR	SN74LVC1G14DBVR	TLV431IDBVRE4	SN74LVC1GU04DBVT				
SN74AHC1G02DBVRE4	SN74LVC1G14DBVRE4	TLV431IDBVRG4	TL431CDBVT				

SN74AHC1G02DBVRG4	SN74LVC1G14DBVRG4	TS5A3166DBVR	TS5A4595DBVR
SN74AHC1G04DBVR	SN74LVC1G240DBVR	TS5A3166DBVRE4	
SN74AHC1G04DBVRE4	SN74LVC1G32DBVR	TS5A3166DBVRG4	
SN74AHC1G04DBVRG4	SN74LVC1G32DBVRE4	TS5A4594DBVR	

**Qualification Data: Group 1 Devices** 

Qua	ilification Data	: Group I Devi	ces			
This qualification has been developed for the validation of this change. The qualification data						
validates that the proposed change meets the applicable released technical specifications.						
Qu	al Vehicle 1: TPA201		)C)			
	Package Constr	ruction Details				
Assembly Site:	TI-Clark	Mold Compound:		4208625		
# Pins-Designator, Family:	20-RTJ, QFN	Mount Compou	nd:	4207	768	
Lead frame (Finish, Base):	NiPdAu, Cu	Bond Wi	ire:	0.96	Mil Dia.,	Cu
Qualification: Plan			1			
				San	nple Size/Fail	
Reliability Test	Conditions		Lot	# 1	Lot# 2	Lot# 3
**High Temp Storage Bake	170C (420 Hrs)		86	5/0	87/0	87/0
**Autoclave	121C (240 Hrs)			'/0	87/0	87/0
**T/C -65C/150C	-65C/+150C (500 C)	/c)	77	'/0	77/0	77/0
X-ray	(top side only)	•	5,	/0	5/0	-
Salt Atmosphere	24 Hours		22	2/0	22/0	22/0
Surface Mount Solderability	8 Hours Steam Age-	Pb Free Solder	22/0		22/0	22/0
Manufacturability (Assembly)	(per mfg. Site specif	ication)	Pass		Pass	Pass
Moisture Sensitivity	(level 2 @ 260C peal		12/0		12/0	12/0
	sequence: Level 2-2600					
Qu	al Vehicle 2: TPS25		C)			
Package Construction Details						
Assembly Site:	TI-Clark	Mold Compour	nd:	4208	625	
# Pins-Designator, Family:	16-RTE, QFN	Mount Compour	Mount Compound: 4207768			
Lead frame (Finish, Base):	NiPdAu, Cu	Bond Wi	ire: 2.0 Mil Dia., Cu			u
Qualification:  Plan			,			
Reliability Test	Conditions		Sample Size/Fail		'Fail	
Reliability Test	Conditions	Conditions		# 1	Lot# 2	Lot# 3
** Life Test	150C (408 Hrs)		77/0		77/0	77/0
**High Temp Storage Bake 175C (500 Hrs)			78/0		80/0	79/0
**Autoclave 121C (240 Hrs)			87/0		87/0	87/0
**Biased HAST 130C/85%RH (96 Hrs)		rs)	77	'/0	77/0	77/0
**Temperature Cycle	-65C/+150C (500 C)	/c)	77	'/0	77/0	77/0
Surface Mount Solderability	Pb Free/Solder-		15	5/0	15/0	-
Manufacturability (Assembly)	(per mfg. Site specif	ication)	Pass		Pass	Pass
Moisture Sensitivity	(level 2 @ 260C peal		12	2/0	12/0	12/0
Notes **- Preconditioning	sequence: Level 2-2600	_				

## **Qualification Data: Group 2 Devices**

Quamication Bata 1 Group 2 Bevices								
This qualification has been developed for the validation of this change. The qualification data								
	validates that the proposed change meets the applicable released technical specifications.							
Qua	I Vehicle 1: DRV916	570PHPR (MSL 3-26	0C)					
Package Construction Details								
Assembly Site:	TAI	Mold Compou	nd:	4205	443			
# Pins-Designator, Family:	48-PHP, HTQFP	Mount Compou	nd:	4208	458			
Lead frame (Finish, Base):	NiPdAu, Cu	Bond W	ire:	0.80	Mil Dia.,	Cu		
Qualification:  Plan								
Reliability Test	Conditions		Sample Size/Fail		'Fail			
Reliability Test	Conditions		Lot	# 1	Lot# 2	Lot# 3		
Electrical Characterization -			Pass		Pass	Pass		
**High Temp Storage Bake	170C (420 Hrs)	170C (420 Hrs)			77/0	77/0		
**Autoclave	121C (96 Hrs)		77	7/0	77/0	77/0		
** Temperature Cycle	-65C/+150C (500 Cy	/c)	77/0		77/0	77/0		
ESD CDM +/- 250V; +/- 1500V			3	/0	-	-		
ESD HBM +/- 1000V; +/- 2500V			3	/0	-	ı		
Manufacturability (Assembly) (per mfg. Site specification)			Pa	ass	Pass	Pass		
Moisture Sensitivity (level 3 @ 260C peak +5/-0C)			12	2/0	-	-		
Notes **- Preconditioning sequence: Level 3-260C.								

## Qualification Data : Group 3 Devices

Qualification Data: Group 3 Devices							
This qualification has been developed for the validation of this change. The qualification data							
validates that the proposed of	change meets the applic	cable released technica	l spe	cificat	tions.		
Qual Vehicle 1: SN74AHC1G126DBVR (MSL 1-260C)							
	Package Constr	ruction Details					
Assembly Site:	HNT	Mold Compou	nd:	4504	13		
# Pins-Designator, Family:	Mount Compou	nd:	4001	54			
Lead frame (Finish, Base):	NiPdAu, Cu	Bond Wi	re:	1.0 M	Mil Dia., Cu		
Qualification:  Plan  Test Results							
Deliebility, Teet	Conditions		Sample Size/Fail			'Fail	
Reliability Test	Conditions			# 1	Lot# 2	Lot# 3	
**High Temp Storage Bake	170C (600 Hrs)		82/0		85/0	84/0	
**Autoclave	121C (192 Hrs)	121C (192 Hrs)		7/0	77/0	77/0	
** Temperature Cycle	-65C/+150C (500 Cy	rc) 77/0 77		77/0	77/0		
Moisture Sensitivity	(level 1 @ 260C peal	k +5/-0C)	<del>                                     </del>		22/0	22/0	
Notes **- Preconditioning	sequence: Level 1-2600	<u></u>					

Qual Vehicle 2: SN74CBTLV1G125DBVR (MSL 1-260C)							
	Package Constr	uction Details					
Assembly Site:	Mold Compour	nd:	450413				
# Pins-Designator, Family: 5-DBV, SOT-23		Mount Compound:		4001	54		
Lead frame (Finish, Base):	NiPdAu, Cu	Bond Wi		0.8 N	1il Dia., C	u	
Qualification:	☐ Test Results				,		
Reliability Test	Conditions		Sample Size/Fail				
**High Temp Storage Bake	170C (600 Hrs)				90/0		
**Autoclave	121C (96 Hrs)				77/0		
**T/C -65C/150C	-65C/+150C (500 Cy	/c)			77/0		
	sequence: Level 1-2600	2.			•		
	Vehicle 3: SN74LVC1		260	C)			
	Package Constr	uction Details					
Assembly Site:	HNT	Mold Compou	nd:	4504	13		
# Pins-Designator, Family:	5-DBV, SOT-23	Mount Compour	nd:	4001	54		
Lead frame (Finish, Base):	NiPdAu, Cu	Bond Wi	re:	0.80	Mil Dia.,	Cu	
Qualification: Plan	☐ Test Results				,		
Delia bilita a Tanak	Canaditiana			San	nple Size/	e/Fail	
Reliability Test	Conditions		Lo	t# 1	Lot# 2	Lot# 3	
**High Temp Storage Bake	170C (420 Hrs)		8	7/0	87/0	89/0	
**Autoclave	121C (192 Hrs)		7	7/0	77/0	77/0	
**Biased HAST	130C/85%RH (192 H	lrs)	8	0/0	80/0	80/0	
** Temperature Cycle	-65C/+150C (500 Cy	/c)	7	7/0	77/0	77/0	
Solderability	Pb Free/Solder			2/0	22/0	22/0	
Manufacturability (Assembly	(per mfg. Site specification)		Pass		Pass	Pass	
Moisture Sensitivity	(level 1 @ 260C peal	OC peak +5/-0C)		2/0	22/0	22/0	
Notes **- Preconditioning	sequence: Level 1-2600	<u>.                                    </u>					
Q	ual Vehicle 4: TS321		<u>:)</u>				
	Package Constr	ruction Details		ı			
Assembly Site:	HNT	Mold Compou	Mold Compound: 4		13		
# Pins-Designator, Family:	5-DBV, SOT-23	Mount Compound: 400154		54	54		
Lead frame (Finish, Base):	NiPdAu, Cu	Bond Wi	ire:	1.0 №	1il Dia., C	u	
Qualification:  Plan	☐ Test Results						
Daliability Task	Conditions		Sample Size/Fail		Fail		
Reliability Test	Conditions		Lot# 1		Lot# 2	Lot# 3	
**High Temp Storage Bake 170C (420 Hrs)				9/0	80/0	80/0	
**Autoclave 121C (192 Hrs)				7/0	77/0	77/0	
** Temperature Cycle	-65C/+150C (500 Cy	/c)		7/0	77/0	77/0	
Moisture Sensitivity	(level 1 @ 260C peal			2/0	22/0	22/0	
,	sequence: Level 1-2600			-			
	-						

Qual Vehicle 5: TS5A3166DBVR (MSL 1-260C)							
Package Construction Details							
Assembly Site:	HNT	Mold Compound	: 450413				
# Pins-Designator, Family:	5-DBV, SOT-23	Mount Compound	: 400154				
Lead frame (Finish, Base):	NiPdAu, Cu	Bond Wire	: 0.8 Mil Dia., Cu				
Qualification:  Plan	Qualification:  Plan  Test Results						
Reliability Test	Conditions		Sample Size/Fail				
**Autoclave	121C (96 Hrs)		77/0				
** Temperature Cycle	-65C/+150C (500 Cyc)		77/0				
Notes **- Preconditioning sequence: Level 1-260C.							

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com